

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/083,596	OYAKE ET AL.	
Examiner		Martin J Angebranndt	Art Unit	Page 1 of 1

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	C	US-6,465,149	10-2002	Kamijima et al.	430/270.1
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	U	Jenkins et al., 'Fundamentals of Optics', (1976) pp. 655
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.